

EMC Test Report

Project No. : 1503C222

Equipment: Gaming Mouse Mat

Model Name : RZ02-0135 Applicant : RAZER INC.

Address : 2035 Corte Del Nogal, Suite 101. Carlsbad California

92011. USA

Date of Receipt : Mar. 26, 2015

Date of Test : Mar. 26, 2015 ~ Apr. 29, 2015

Issued Date : May. 04, 2015 Tested by : BTL Inc.

Testing Engineer

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(James Chiu)

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Report No.: BTL-EMC-1-1503C222



Declaration

BTL represents to the client that testing is done in accordance with standard procedures as applicable and that test instruments used has been calibrated with the standards traceable to National Measurement Laboratory (**NML**) of **R.O.C**, or National Institute of Standards and Technology (**NIST**) of **U.S.A.**

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For the use of the authority's logo is limited unless the Test Standard(s)/Scope(s)/Item(s) mentioned in this test report is (are) included in the conformity assessment authorities acceptance respective.

Report No.: BTL-EMC-1-1503C222 Page 2 of 53



Table of Contents	Page
REPORT ISSUED HISTORY	6
1. CERTIFICATION	7
2 . SUMMARY OF TEST RESULTS	8
2.1 TEST FACILITY	9
2.2 MEASUREMENT UNCERTAINTY	9
3 . GENERAL INFORMATION	10
3.1 GENERAL DESCRIPTION OF EUT	10
3.2 DESCRIPTION OF TEST MODES	11
3.3 BLOCK DIAGRAM SHOWING THE CONFIGURATION OF SYSTEM TESTED	12
3.4 DESCRIPTION OF SUPPORT UNITS	13
4 . EMC EMISSION TEST	14
4.1 CONDUCTED EMISSION MEASUREMENT	14
4.1.1 POWER LINE CONDUCTED EMISSION 4.1.2 MEASUREMENT INSTRUMENTS LIST	14 14
4.1.3 TEST PROCEDURE	15
4.1.4 DEVIATION FROM TEST STANDARD	15
4.1.5 TEST SETUP 4.1.6 EUT USB CONDITIONS	15 15
4.1.7 TEST RESULTS	16
4.2 RADIATED EMISSION MEASUREMENT	19
4.2.1 LIMITS OF RADIATED EMISSION MEASUREMENT	19
4.2.2 MEASUREMENT INSTRUMENTS LIST 4.2.3 TEST PROCEDURE	20 20
4.2.4 DEVIATION FROM TEST STANDARD	20
4.2.5 TEST SETUP- BELOW 1 GHZ	21
4.2.6 EUT USB CONDITIONS 4.2.7 TEST RESULTS-BETWEEN 30MHZ AND 1000MHZ	21 21
5 . EMC IMMUNITY TEST	24
5.1 STANDARD COMPLIANCE/SEVERITY LEVEL/CRITERIA	24
5.2 GENERAL PERFORMANCE CRITERIA 5.3 GENERAL PERFORMANCE CRITERIA TEST SETUP	25 25
5.4 ESD TESTING	25 26
5.4.1 TEST SPECIFICATION	26 26
5.4.2 MEASUREMENT INSTRUMENTS	26

Report No.: BTL-EMC-1-1503C222



Table of Contents	Page
5.4.3 TEST PROCEDURE 5.4.4 DEVIATION FROM TEST STANDARD 5.4.5 TEST SETUP 5.4.6 TEST RESULTS	26 27 27 28
5.4.7 PHOTO(S) SHOWN THE LOCATION(S) OF ESD EVALUATED	29
5.5 RS TESTING 5.5.1 TEST SPECIFICATION 5.5.2 MEASUREMENT INSTRUMENTS 5.5.3 TEST PROCEDURE 5.5.4 DEVIATION FROM TEST STANDARD 5.5.5 TEST SETUP 5.5.6 TEST RESULTS	30 30 30 30 30 31
5.6.6 TEST RESULTS 5.6 EFT/BURST TESTING 5.6.1 TEST SPECIFICATION 5.6.2 MEASUREMENT INSTRUMENTS 5.6.3 TEST PROCEDURE 5.6.4 DEVIATION FROM TEST STANDARD 5.6.5 TEST SETUP 5.6.6 TEST RESULTS	32 33 33 33 33 34 36
5.7 SURGE TESTING 5.7.1 TEST SPECIFICATION 5.7.2 MEASUREMENT INSTRUMENTS 5.7.3 TEST PROCEDURE 5.7.4 DEVIATION FROM TEST STANDARD 5.7.5 TEST SETUP 5.7.6 TEST RESULTS	37 37 37 37 38 38 38
5.8 INJECTION CURRENT TESTING 5.8.1 TEST SPECIFICATION 5.8.2 MEASUREMENT INSTRUMENTS 5.8.3 TEST PROCEDURE 5.8.4 DEVIATION FROM TEST STANDARD 5.8.5 TEST SETUP 5.8.6 TEST RESULTS	40 40 40 40 40 41 42
5.9 POWER FREQUENCY MAGNETIC FIELD TESTING 5.9.1 TEST SPECIFICATION 5.9.2 MEASUREMENT INSTRUMENTS 5.9.3 TEST PROCEDURE 5.9.4 DEVIATION FROM TEST STANDARD 5.9.5 TEST SETUP 5.9.6 TEST RESULTS 5.10 VOLTAGE INTERRUPTION/DIPS TESTING	43 43 43 43 44 45

Report No.: BTL-EMC-1-1503C222



Table of Contents	Dawa
Table of Contents	Page
5.10.1 TEST SPECIFICATION	46
5.10.2 MEASUREMENT INSTRUMENTS	46
5.10.3 TEST PROCEDURE	46
5.10.4 DEVIATION FROM TEST STANDARD	46
5.10.5 TEST SETUP	47
5.10.6 TEST RESULTS	48
6 . EUT TEST PHOTO	49

Report No.: BTL-EMC-1-1503C222 Page 5 of 53



REPORT ISSUED HISTORY

Issued No.	Description	Issued Date
BTL-EMC-1-1503C222	Original Issue.	May. 04, 2015

Report No.: BTL-EMC-1-1503C222 Page 6 of 53



1. CERTIFICATION

Equipment : Gaming Mouse Mat

Brand Name : RAZER
Model Name : RZ02-0135
Applicant : RAZER INC.

Manufacturer : Razer (Asia-Pacific) Pte Ltd.

Address : 514 Chai Chee Lane #07-01 ~ 06 Singapore 469029

Factory : RAZER TECHNOLOGY AND DEVELOPMENT (SHENZHEN) CO., LTD. Address : East Wing, 3rd Floor, Block 2, Phase 1 of Vision Shenzhen Business Park

Keji South Road, Hi-Tech Industrial Park, Shenzhen 518057, China

Date of Test : Mar. 26, 2015 ~ Apr. 29, 2015 Test Sample : ENGINEERING SAMPLE

Standard(s) : EN 55022:2010+AC:2011 Class B

EN 55024:2010 IEC 61000-4-2: 2008

IEC 61000-4-3: 2006+A1:2007+A2:2010

IEC 61000-4-4: 2012 IEC 61000-4-5: 2014 IEC 61000-4-6: 2013 IEC 61000-4-8: 2009 IEC 61000-4-11: 2004

The above equipment has been tested and found compliance with the requirement of the relative standards by BTL Inc.

The test data, data evaluation, and equipment configuration contained in our test report (Ref No. BTL-EMC-1-1503C222) were obtained utilizing the test procedures, test instruments, test sites that has been accredited by the Authority of TAF according to the ISO-17025 quality assessment standard and technical standard(s).

Report No.: BTL-EMC-1-1503C222 Page 7 of 53



2. SUMMARY OF TEST RESULTS

Test procedures according to the technical standards:

EMC Emission				
Standard(s)	Test Item	Limit	Judgment	Remark
EN 55022:2010+AC:2011	Conducted Emission	Class B	PASS	
EN 55022:2010+AC:2011	Radiated Emission	Class B	PASS	
EN 61000-3-2: 2014	Harmonic Current Emission	Class A	N/A	NOTE (1)
EN 61000-3-3:2013	Voltage Fluctuations & Flicker		N/A	NOTE (1)
EMC Immunity EN 55024:2010				
Section	Test Item	Criteria	Judgment	Remark
IEC 61000-4-2:2008	Electrostatic Discharge	В	PASS	
IEC 61000-4-3: 2006+A1:2007+A2:2010	RF electromagnetic field	А	PASS	
IEC 61000-4-4: 2012	Fast transients	В	PASS	
IEC 61000-4-5:2014	Surges	В	PASS	
IEC 61000-4-6:2013	Injected Current	Α	PASS	
IEC 61000-4-8:2009	Power Frequency Magnetic Field	А	PASS	
IEC 61000-4-11:2004	Volt. Interruptions Volt. Dips	B / C / C NOTE (3)	PASS	

NOTE:

- (1) " N/A" denotes test is applicable to this device.
- (2) If the EUT's category is Class D and power consumption is less than 75W, there is no limit applied.
- (3) Voltage dip: >95% reduction Performance Criteria **B** Voltage dip: 30% reduction Performance Criteria **C**

Voltage dip. 30 % reduction – Performance Criteria C

Voltage Interruption: >95% reduction – Performance Criteria **C**

Report No.: BTL-EMC-1-1503C222 Page 8 of 53



2.1 TEST FACILITY

The test facilities used to collect the test data in this report is at the location of No.3, Jinshagang 1st Road, Shixia, Dalang Town, Dongguan, Guangdong, China.

2.2 MEASUREMENT UNCERTAINTY

Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. The BTL measurement uncertainty is less than the CISPR 16-4-2 U_{cispr} requirement.

The reported uncertainty of measurement $\mathbf{y} \pm \mathbf{U}$, where expanded uncertainty \mathbf{U} is based on a standard uncertainty multiplied by a coverage factor of $\mathbf{k=2}$, providing a level of confidence of approximately 95%.

A. Conducted Measurement:

Test Site	Method	Measurement Frequency Range	U,(dB)	Note
DG-C01	CISPR	150 kHz ~ 30MHz	3.4	

B. Radiated Measurement:

Test Site	Method	Measurement Frequency Range	Ant. H / V	U,(dB)	Note
		30MHz ~ 200MHz	V	4.04	
DG-CB08 (10m) CISPR	30MHz ~ 200MHz	Н	4.04		
(10m)	CIOPK	200MHz ~ 1,000MHz	V	4.08	
		200MHz ~ 1,000MHz	Н	4.02	

C. Immunity Measurement:

Test Site	Method	Test item	U	Note
SR02	IEC 61000-4-2	Voltage (2KV/4KV/6KV/8KV/15KV/25 KV/30 KV)	1.3%	
		Current	3%	
CB05	IEC 61000-4-3	80MHz~3GHz	2.875	
SR05	IEC 61000-4-4	Impulse Amplitude	4 %	
SKUS	IEC 61000-4-4	Timing	3 %	
SR05	IEC 61000-4-5	Impulse Amplitude	4 %	
SKUS	160 61000-4-3	Timing	3 %	
CB06	IEC 61000-4-6	CDN: 150kHz~80MHz	1.988 dB	
CDUO	IEC 01000-4-0	EM Clamp: 150kHz~80MHz	1.777 dB	
TR06	IEC 61000-4-8	Magnetic Field Level	3 %	
SR05	IEC 61000-4-11	Impulse Amplitude	4 %	
SRUS	160 01000-4-11	Timing	3 %	

Note: Unless specifically mentioned, the uncertainty of measurement has not been taken into account to declare the compliance or non-compliance to the specification.

Report No.: BTL-EMC-1-1503C222 Page 9 of 53



3. GENERAL INFORMATION

3.1 GENERAL DESCRIPTION OF EUT

Equipment	Gaming Mouse Mat
Brand Name	RAZER
Model Name	RZ02-0135
Model Difference	N/A
Power Source	Supplied from USB port.
Power Rating	DC 5V

Note:

- 1. For a more detailed features description, please refer to the manufacturer's specifications or the User's Manual.
- 2. The maximum operating frequency is 48MHz.

Report No.: BTL-EMC-1-1503C222 Page 10 of 53



3.2 DESCRIPTION OF TEST MODES

To investigate the maximum EMI emission characteristics generated from EUT, the test system was pre-scanning tested base on the consideration of following EUT operation mode or test configuration mode which possible have effect on EMI emission level. Each of these EUT operation mode(s) or test configuration mode(s) mentioned above was evaluated respectively.

Pretest Mode	Description
Mode 1	USB

The EUT system operated these modes were found to be the worst case during the pre-scanning test as following:

For Conducted Test		
Final Test Mode	Description	
Mode 1	USB	

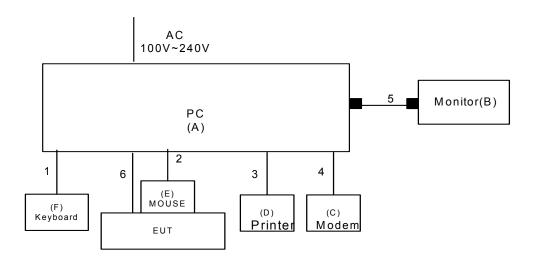
For Radiated Test		
Final Test Mode	Description	
Mode 1	USB	

For EMS Test				
Final Test Mode	Description			
Mode 1	USB			

Report No.: BTL-EMC-1-1503C222 Page 11 of 53



3.3 BLOCK DIAGRAM SHOWING THE CONFIGURATION OF SYSTEM TESTED



■Ferrite core

Report No.: BTL-EMC-1-1503C222 Page 12 of 53



3.4 DESCRIPTION OF SUPPORT UNITS

The EUT has been tested as an independent unit together with other necessary accessories or support units. The following support units or accessories were used to form a representative test configuration during the tests.

Item	Equipment	Mfr/Brand	Model/Type No.	FCC ID	Series No.	Note
Α	PC	Dell 745	DCSM	DOC	G7K832X	
В	Monitor	DELL	E117FPC	DOC	CN-OFJ179-64180-6AG-IWNS	
С	Modem	ACEEX	DM-1414V	DOC	0603002131	
D	Printer	SII	DPU-414	DOC	018507 B	
Е	Mouse	Dell	L100	DOC	CNORH6596589071T08NE	
F	USB	Dell	L100	DOC	CNORH6596589071T08NE	
	Keyboard					

Item	Shielded Type	Ferrite Core	Length	Note
1	YES	NO	1.8m	USB Cable
2	YES	NO	1.8m	USB Cable
3	YES	NO	1.5m	Parallel Cable
4	YES	NO	1.5m	RS232 Cable
5	YES	YES	1.5m	D-SUB Cable
6	YES	NO	2.1m	USB Cable

Note:

- (1) The support equipment was authorized by Declaration of Conformity.
- (2) For detachable type I/O cable should be specified the length in m in <code>[Length]</code> column.

Report No.: BTL-EMC-1-1503C222 Page 13 of 53



4. EMC EMISSION TEST

4.1CONDUCTED EMISSION MEASUREMENT

4.1.1 POWER LINE CONDUCTED EMISSION (FREQUENCY RANGE 150KHZ-30MHZ)

FREQUENCY (MHz)	Class A	(dBuV)	Class B (dBuV)		
FREQUENCT (IVIIIZ)	Quasi-peak	Average	Quasi-peak	Average	
0.15 -0.5	79.00	66.00	66 - 56 *	56 - 46 *	
0.50 -5.0	73.00	60.00	56.00	46.00	
5.0 -30.0	73.00	60.00	60.00	50.00	

Note:

- (1) The tighter limit applies at the band edges.
- (2) The limit of " * " marked band means the limitation decreases linearly with the logarithm of the frequency in the range.
- (3) The test result calculated as following:

 Measurement Value = Reading Level + Correct Factor

 Correct Factor = Insertion Loss + Cable Loss + Attenuator Factor(if use)

 Margin Level = Measurement Value Limit Value

4.1.2 MEASUREMENT INSTRUMENTS LIST

Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Calibrated until
1	Artificial-Mains Network	SCHWARZBECK	NSLK 8127	8127685	Dec. 05, 2015
2	LISN	R&S	ENV216	100526	Mar. 28, 2016
3	Test Cable	N/A	RG400 12m	N/A	Mar. 12, 2016
4	EMI Test Receiver	R&S	ESCS30	826547/022	Mar. 28, 2016
5	50Ω Terminator	SHX	TF2-3G-A	08122901	Mar. 28, 2016
6	Measurement Software	Farad	EZ-EMC Ver.NB-03A1 -01	N/A	N/A

Remark: "N/A" denotes no model name, serial no. and no calibration specified.

Report No.: BTL-EMC-1-1503C222 Page 14 of 53



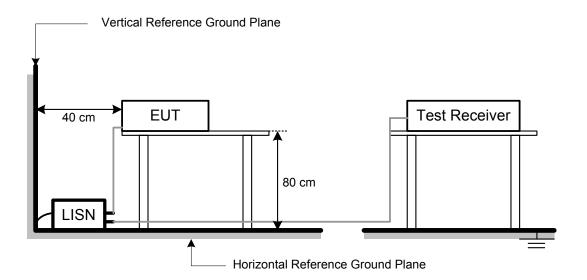
4.1.3 TEST PROCEDURE

- a. The EUT was placed 0.8 meters from the horizontal ground plane with EUT being connected to the power mains through a line impedance stabilization network (LISN). All other support equipments powered from additional LISN(s). The LISN provide 50 Ohm/ 50uH of coupling impedance for the measuring instrument.
- b. Interconnecting cables that hang closer than 40 cm to the ground plane shall be folded back and forth in the center forming a bundle 30 to 40 cm long.
- c. I/O cables that are not connected to a peripheral shall be bundled in the center. The end of the cable may be terminated, if required, using the correct terminating impedance. The overall length shall not exceed 1 m.
- d. LISN at least 80 cm from nearest part of EUT chassis.
- e. For the actual test configuration, please refer to the related Item -EUT Test Photos.

4.1.4 DEVIATION FROM TEST STANDARD

No deviation

4.1.5 TEST SETUP



4.1.6 EUT USB CONDITIONS

The EUT exercise program used during radiated and/or conducted emission measurement was designed to exercise the various system components in a manner similar to a typical use.

Report No.: BTL-EMC-1-1503C222 Page 15 of 53



4.1.7 TEST RESULTS

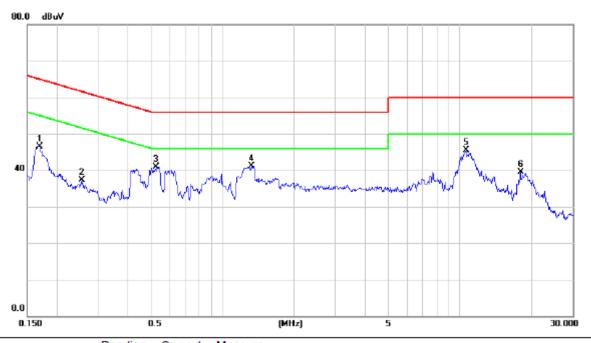
Remark:

- (1) Reading in which marked as QP means measurements by using are Quasi-Peak Mode with Detector BW=9KHz;SPA setting in RBW=10KHz,VBW =10KHz, Swp. Time = 0.3 sec./MHz
 Reading in which marked as AV means measurements by using are Average Mode with instrument setting in RBW=10KHz,VBW=10KHz, Swp. Time =0.3 sec./MHz
- (2) All readings are QP Mode value unless otherwise stated AVG in column of Note ... If the QP Mode Measured value compliance with the QP Limits and lower than AVG Limits, the EUT shall be deemed to meet both QP & AVG Limits and then only QP Mode was measured, but AVG Mode didn't perform on this case, a " * " marked in AVG Mode column of Interference Voltage Measured on the Note of Interference Voltage Measured on the Note
- (3) Measuring frequency range from 150KHz to 30MHz o

Report No.: BTL-EMC-1-1503C222 Page 16 of 53



E.U.T:	Gaming Mouse Mat	Model Name :	RZ02-0135
Temperature :	21° C	Relative Humidity:	51 %
Pressure:	1008 hPa	Test Voltage :	AC 230V/50Hz
Test Mode :	USB	Phase :	Line

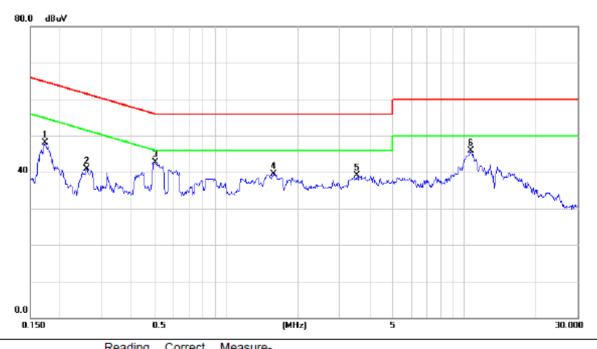


No. I	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Margin		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1		0.1695	37.01	9.53	46.54	64.98	-18.44	peak	
2		0.2553	27.77	9.55	37.32	61.58	-24.26	peak	
3		0.5262	31.41	9.59	41.00	56.00	-15.00	peak	
4		1.3290	31.53	9.66	41.19	56.00	-14.81	peak	
5	*	10.6364	35.36	10.13	45.49	60.00	-14.51	peak	
6		18.0393	29.17	10.37	39.54	60.00	-20.46	peak	

Report No.: BTL-EMC-1-1503C222 Page 17 of 53



E.U.T:	Gaming Mouse Mat	Model Name :	RZ02-0135
Temperature :	21° C	Relative Humidity:	51 %
Pressure:	1008 hPa	Test Voltage :	AC 230V/50Hz
Test Mode :	USB	Phase :	Neutral



No.	Mk.	Freq.	Level	Factor	measure- ment	Limit	Margin		
		MHz	dBuV	dB	dBuV	dBuV	dB	Detector	Comment
1		0.1733	38.55	9.52	48.07	64.80	-16.73	peak	
2		0.2590	31.37	9.54	40.91	61.46	-20.55	peak	
3	*	0.5020	33.17	9.58	42.75	56.00	-13.25	peak	
4		1.5850	29.90	9.67	39.57	56.00	-16.43	peak	
5		3.5278	29.23	9.79	39.02	56.00	-16.98	peak	
6		10.6990	35.66	10.21	45.87	60.00	-14.13	peak	



4.2 RADIATED EMISSION MEASUREMENT

4.2.1 LIMITS OF RADIATED EMISSION MEASUREMENT

Below 1 GHz

FREQUENCY (MHz)	Class A (at 10m)	Class B (at 10m)	
FREQUENCT (IVIIIZ)	dBuV/m	dBuV/m	
30 – 230	40	30	
230 – 1000	47	37	

Notes:

- (1) The limit for radiated test was performed according to as following: CISPR 22.
- (2) The tighter limit applies at the band edges.
- (3) Emission level (dBuV/m)=20log Emission level (uV/m).
- (4) The test result calculated as following: Measurement Value = Reading Level + Correct Factor Correct Factor = Antenna Factor + Cable Loss - Amplifier Gain(if use) Margin Level = Measurement Value - Limit Value

FREQUENCY RANGE OF RADIATED MEASUREMENT

THE GOETOT TO THOSE OF TO TODAY THE METODINE METO					
Highest frequency generated or Upper frequency of measurement used in the device or on which the device operates or tunes (MHz)	Range (MHz)				
Below 1.705	30				
1.705 - 108	1000				
108 - 500	2000				
500 - 1000	5000				

Report No.: BTL-EMC-1-1503C222 Page 19 of 53



4.2.2 MEASUREMENT INSTRUMENTS LIST

Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Calibrated until
1	Antenna	EMCO	3142C	00066462	Mar. 28, 2016
2	Antenna	EMCO	3142C	00066464	Mar. 28, 2016
3	Amplifier	Agilent	8447D	2944A11203	Nov. 02, 2015
4	Amplifier	Agilent	8447D	2944A11204	Nov. 02, 2015
5	Spectrum Analyzer	Agilent	E4443A	MY48250370	Nov. 02, 2015
6	RF Pre-selector	Agilent	N9039A	MY46520201	Nov. 02, 2015
7	Test Cable	N/A	Cable_5m_8 m_15m	N/A	Jan. 04, 2016
8	Test Cable	N/A	Cable_5m_1 1m_15m	N/A	Jan. 04, 2016
9	Spectrum Analyzer	Agilent	E4447A	MY48250208	Nov. 02, 2015
10	RF Pre-selector	Agilent	N9039A	MY46520214	Nov. 02, 2015
11	Multi-Device Controller	ETS-Lindgren	2090	N/A	N/A
12	Measurement Software	Farad	EZ-EMC Ver.BTL-2AN T-1	N/A	N/A

Remark: "N/A" denotes no model name, serial no. and no calibration specified.

4.2.3 TEST PROCEDURE

- a. The EUT was placed on the top of a rotating table 0.8 meters above the ground at a 10 meter semi-anechoic chamber. The table was rotated 360 degrees to determine the position of the highest radiation.
- b. The height of the equipment or of the substitution antenna shall be 0.8 m; the height of the test antenna shall vary between 1 m to 4 m. Both horizontal and vertical polarizations of the antenna are set to make the measurement.
- c. The initial step in collecting radiated emission data is a spectrum analyzer peak detector mode pre-scanning the measurement frequency range. Significant peaks are then marked and then Quasi Peak detector mode re-measured.
- d. If the Peak Mode measured value compliance with and lower than Quasi Peak Mode Limit, the EUT shall be deemed to meet QP Limits and then no additional QP Mode measurement performed.
- e. For the actual test configuration, please refer to the related Item –EUT Test Photos.

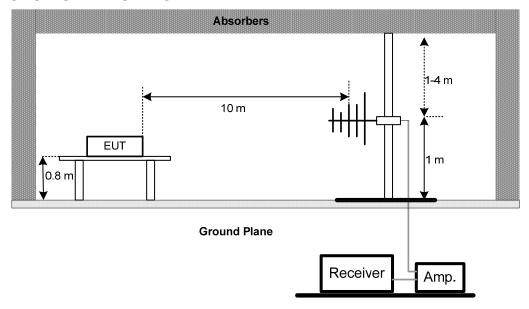
4.2.4 DEVIATION FROM TEST STANDARD

No deviation

Report No.: BTL-EMC-1-1503C222 Page 20 of 53



4.2.5 TEST SETUP- BELOW 1 GHZ



4.2.6 EUT USB CONDITIONS

The EUT tested system was configured as the statements of **4.1.6** Unless otherwise a special operating condition is specified in the follows during the testing.

4.2.7 TEST RESULTS-BETWEEN 30MHZ AND 1000MHZ

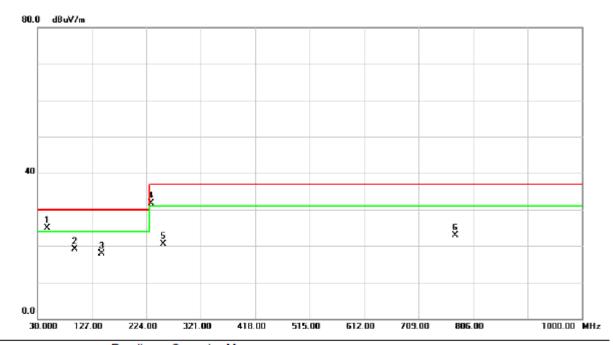
Remark:

- (1) Reading in which marked as QP or Peak means measurements by using are Quasi-Peak Mode or Peak Mode with Detector BW=120KHz ; SPA setting in RBW=120KHz, VBW =120KHz, Swp. Time = $0.3 \text{ sec./MHz} \circ$
- (2) All readings are Peak unless otherwise stated QP in column of \lceil Note $_{
 m l}$. Peak denotes that the Peak reading compliance with the QP Limits and then QP Mode measurement didn't perform $_{
 m o}$
- (3) Measuring frequency range from 30MHz to 1000MHz o
- (4) If the peak scan value lower limit more than 20dB, then this signal data does not show in table \circ

Report No.: BTL-EMC-1-1503C222 Page 21 of 53



E.U.T:	Gaming Mouse Mat	Model Name :	RZ02-0135
Temperature :	25° C	Relative Humidity:	60 %
Pressure:	1008 hPa	Test Voltage :	AC 230V/50Hz
Test Mode :	USB	Polarization :	Vertical



	No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Margin		
-			MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector	Comment
	1	*	47.4600	42.75	-17.83	24.92	30.00	-5.08	peak	
	2		95.9600	37.93	-18.84	19.09	30.00	-10.91	peak	
	3		144.4600	36.00	-18.14	17.86	30.00	-12.14	peak	
	4	į	232.7300	45.25	-13.62	31.63	37.00	-5.37	peak	
	5		254.0700	33.06	-12.59	20.47	37.00	-16.53	peak	
_	6		773.9900	23.99	-1.13	22.86	37.00	-14.14	peak	

Report No.: BTL-EMC-1-1503C222 Page 22 of 53



E.U.T:	Gaming Mouse Mat	Model Name :	RZ02-0135
Temperature :	25° C	Relative Humidity:	60 %
Pressure:	1008 hPa	Test Voltage :	AC 230V/50Hz
Test Mode:	USB	Polarization :	Horizontal



No.	Mk.	Freq.	Level	Factor	ment	Limit	Margin			
		MHz	dBuV	dB	dBuV/m	dBuV/m	dB	Detector	Comment	
1		45.5200	38.80	-17.25	21.55	30.00	-8.45	peak		
2	*	81.4100	44.27	-20.38	23.89	30.00	-6.11	peak		
3		191.9900	34.95	-15.71	19.24	30.00	-10.76	peak		
4		232.7300	39.75	-13.62	26.13	37.00	-10.87	peak		
5	-	450.0100	30.87	-7.55	23.32	37.00	-13.68	peak		
6		786.6000	25.48	-1.13	24.35	37.00	-12.65	peak		



5. EMC IMMUNITY TEST

5.1 STANDARD COMPLIANCE/SEVERITY LEVEL/CRITERIA

Tests Standard No.	TEST SPECIFICATION Level	Test Mode Test Ports	Criteria
1. ESD	±8kV air discharge ±4kV contact discharge	Direct Mode	В
IEC/EN 61000-4-2	±4kV HCP discharge ±4kV VCP discharge	Indirect Mode	В
2. RS IEC/EN 61000-4-3	80 MHz to 1000 MHz 3V/m(rms), 1 KHz, 80%, AM modulated	Enclosure	Α
3. EFT/Burst	±1.0kV(peak) 5/50ns Tr/Th 5KHz Repetition Freq.	Power Supply Port	В
IEC/EN 61000-4-4	±0.5 kV(peak) 5/50ns Tr/Th 5KHz Repetition Freq.	CTL/Signal Data Line Port	В
4. Surges	±1 kV(5P/5N) 1.2/50(8/20) Tr/Th us	L-N	В
IEC/EN 61000-4-5	±2 kV(5P/5N) 1.2/50(8/20) Tr/Th us	L-PE N-PE	В
	0.15 MHz to 80 MHz 3V(rms), 1KHz 80%, AM Modulated 150Ω source impedance	CTL/Signal Port	А
5 Injected Current IEC/EN 61000-4-6	0.15 MHz to 80 MHz 3V(rms), 1KHz 80%, AM Modulated 150Ω source impedance	AC Power Port	А
	0.15 MHz to 80 MHz 3V(rms), 1KHz 80%, AM Modulated 150Ω source impedance	DC Power Port	А
6. Power Frequency Magnetic Field IEC/EN 61000-4-8	50 Hz/60Hz, 1A/m	Enclosure	А
7. Volt. Interruptions	Voltage dip>95%		В
Volt. Dips IEC/EN 61000-4-11	Voltage dip 30% Interruption>95%	AC Power Port	С
	interruption / 90 /0		С

Report No.: BTL-EMC-1-1503C222 Page 24 of 53



5.2 GENERAL PERFORMANCE CRITERIA

According to EN55024 standard, the general performance criteria as following:

Criterion A	The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.
Criterion B	After the test, the equipment shall continue to operate as intended without operator Intervention. No degradation of performance or loss of function is allowed, after the application of the phenomenon below a performance level specified by the manufacturer, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is allowed. However, no change of operating state if stored data allowed to persist after the test. If the minimum performance level (or the permissible performance loss) is not specified by the manufacturer, then either of these may be derived from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.
Criterion C	Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions. Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

5.3 GENERAL PERFORMANCE CRITERIA TEST SETUP

The EUT tested system was configured as the statements of **4.1.6** Unless otherwise a special operating condition is specified in the follows during the testing.

Report No.: BTL-EMC-1-1503C222 Page 25 of 53



5.4 ESD TESTING

5.4.1 TEST SPECIFICATION

Basic Standard:	IEC/EN 61000-4-2
Discharge Impedance:	330 ohm / 150 pF
Required Performance	В
Discharge Voltage:	Air Discharge: ±2kV/±4kV/±8kV (Direct)
	Contact Discharge: ±2kV/±4kV (Direct/Indirect)
Polarity:	Positive & Negative
Number of Discharge:	Air Discharge: min. 20 times at each test point
	Contact Discharge: min. 200 times in total
Discharge Mode:	Single Discharge
Discharge Period:	1 second minimum

5.4.2 MEASUREMENT INSTRUMENTS

Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Calibrated until
1	ESD Generator	TESEQ AG	NSG 437	450	Jul. 10, 2015

Remark: "N/A" denotes no model name, serial no. and no calibration specified.

5.4.3 TEST PROCEDURE

The test generator necessary to perform direct and indirect application of discharges to the EUT in the following manner:

a. Contact discharge was applied to conductive surfaces and coupling planes of the EUT. During the test, it was performed with single discharges. For the single discharge time between successive single discharges was at least 1 second. The EUT shall be exposed to at least 200 discharges, 100 each at negative and positive polarity, at a minimum of four test points. One of the test points shall be subjected to at least 50 indirect discharges to the center of the front edge of the horizontal coupling plane. The remaining three test points shall each receive at least 50 direct contact discharges.

If no direct contact test points are available, then at least 200 indirect discharges shall be applied in the indirect mode. Test shall be performed at a maximum repetition rate of one discharge per second.

Vertical Coupling Plane (VCP):

The coupling plane, of dimensions 0.5m x 0.5m, is placed parallel to, and positioned at a distance 0.1m from, the EUT, with the Discharge Electrode touching the coupling plane. The four faces of the EUT will be performed with electrostatic discharge.

Horizontal Coupling Plane (HCP):

The coupling plane is placed under to the EUT. The generator shall be positioned vertically at a distance of 0.1m from the EUT, with the Discharge Electrode touching the coupling plane. The four faces of the EUT will be performed with electrostatic discharge.

- b. Air discharges at insulation surfaces of the EUT.
 - It was at least ten single discharges with positive and negative at the same selected point.
- c. For the actual test configuration, please refer to the related Item –EUT Test Photos.

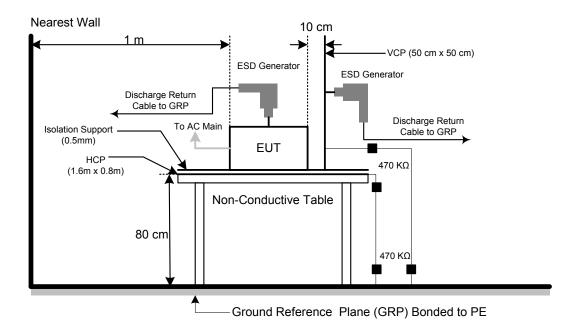
Report No.: BTL-EMC-1-1503C222 Page 26 of 53



5.4.4 DEVIATION FROM TEST STANDARD

No deviation

5.4.5 TEST SETUP



Note:

TABLE-TOP EQUIPMENT

The configuration consisted of a wooden table 0.8 meters high standing on the Ground Reference Plane. The GRP consisted of a sheet of aluminum at least 0.25mm thick, and 2.5 meters square connected to the protective grounding system. A Horizontal Coupling Plane (1.6m x 0.8m) was placed on the table and attached to the GRP by means of a cable with 940k total impedance. The equipment under test, was installed in a representative system as described in section 7 of IEC /EN 61000-4-2, and its cables were placed on the HCP and isolated by an insulating support of 0.5mm thickness. A distance of 1-meter minimum was provided between the EUT and the walls of the laboratory and any other metallic structure.

FLOOR-STANDING EQUIPMENT

The equipment under test was installed in a representative system as described in section 7 of IEC/EN 61000-4-2, and its cables were isolated from the Ground Reference Plane by an insulating support of 0.1meter thickness. The GRP consisted of a sheet of aluminum that is at least 0.25mm thick, and 2.5meters square connected to the protective grounding system and extended at least 0.5 meters from the EUT on all sides.

Report No.: BTL-EMC-1-1503C222 Page 27 of 53



5.4.6 TEST RESULTS

E.U.T:	Gaming Mouse Mat	Model Name :	RZ02-0135
Temperature :	25° C	Relative Humidity:	60 %
Pressure:	1002 hPa	Test Voltage :	AC 230V/50Hz
Test Mode :	USB		

Mode			Air	Dis	charg	ge			Contact Discharge							
	21	۲V	4kV 8kV		- k	٠V	2kV		4kV		- kV		- kV			
Location	Р	Ν	Р	N	Р	N	Р	N	Р	N	Р	N	Р	N	Р	N
1	Α	Α	Α	Α	Α	Α	-	-	Α	Α	Α	Α	-	-	-	-
2	Α	Α	Α	Α	Α	Α	-	-	-	-	-	-	-	-	-	-
3	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
4	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
Criteria		В						-	В				-		_	
Result	Α							-	Α				_		-	
Judgment		PASS						-	PASS			-		-		

Mode			НС	P Di	ischa	rge			VCP Discharge								
	2k	۲V	4	4kV - kV		- kV - kV		2kV		′ 4k		4kV		- kV		- kV	
Location	Р	Ν	Р	N	Р	N	Р	Ν	Р	N	Р	Ν	Р	N	Р	N	
1	Α	Α	Α	Α	-	-	-	-	Α	Α	Α	Α	-	-	-	-	
2	Α	Α	Α	Α	-	-	-	-	Α	Α	Α	Α	-	-	-	-	
3	Α	Α	Α	Α	-	-	-	-	Α	Α	Α	Α	-	-	-	-	
4	Α	Α	Α	Α	-	-	-	-	Α	Α	Α	Α	-	-	-	-	
Criteria		В				-		-	В				-		_		
Result	Α			-	-		Α			_		_					
Judgment	PASS				-		•	PASS			-		-				

Note:

- 1) P/N denotes the Positive/Negative polarity of the output voltage.
- 2) Test condition:
 - Direct / Indirect (HCP/VCP) discharges: Minimum 50 times (Positive/Negative) at each point. Air discharges: Minimum 10 times (Positive/Negative) at each point.
- 3) Test location(s) in which discharge (Air and contact discharge) to be applied illustrated by photos shown in next page(s)
- 4) The Indirect (HCP/VCP) discharges description of test point as following: 1.left side 2.right side 3.front side 4.rear side
- 5) N/A denotes test is not applicable to this device
- 6) Criteria A: No observation of any performance degradation.
- 7) Criteria B: Some degradation of performance is observed but the equipment continues to operate as intended.
- 8) Criteria C: Loss of functionality, but self-recoverable by user, without loss of information or settings.

Report No.: BTL-EMC-1-1503C222 Page 28 of 53



5.4.7 PHOTO(S) SHOWN THE LOCATION(S) OF ESD EVALUATED





Report No.: BTL-EMC-1-1503C222 Page 29 of 53



5.5 RS TESTING

5.5.1 TEST SPECIFICATION

Basic Standard:	IEC/EN 61000-4-3
Required Performance	A
Frequency Range:	80 MHz - 1000 MHz
Field Strength:	3 V/m
Modulation:	1kHz Sine Wave, 80%, AM Modulation
Frequency Step:	1% of fundamental
Polarity of Antenna:	Horizontal and Vertical
Test Distance:	3 m
Antenna Height:	1.5 m
Dwell Time:	at least 3 seconds

5.5.2 MEASUREMENT INSTRUMENTS

Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Calibrated until
1	Digital Signal Generator	HP	ESG-D3000A	US36260188	Mar. 28, 2016
2	Antenna	ETS	3142C	00047662	Mar. 28, 2016
3	Power amplifier	MILMEGA	80RF1000-250	N/A	Nov. 02, 2015
4	Amplifier	AR	50S1G4A	326720	Mar. 28, 2016
5	Measurement Software	TOYO	IM5/R Ver 3.8.050	N/A	N /A

Remark: "N/A" denotes no model name, serial no. and no calibration specified.

5.5.3 TEST PROCEDURE

The EUT and support equipment, which are placed on a table that is 0.8 meter above ground and the testing was performed in a fully-anechoic chamber.

The testing distance from antenna to the EUT was 3 meters.

The other condition as following manner:

- a. The field strength level was 3V/m.
- b. The frequency range is swept from 80 MHz to 1000 MHz, with the signal 80% amplitude modulated with a 1kHz sine wave. The rate of sweep did not exceed 1.5x 10-3 decade/s. Where the frequency range is swept incrementally, the step size was 1% of fundamental.
- c. Sweep Frequency 900 MHz, with the Duty Cycle:1/8 and Modulation: Pulse 217 Hz(if applicable)
- d. The dwell time at each frequency shall be not less than the time necessary for the EUT to be able to respond.
- e. The test was performed with the EUT exposed to both vertically and horizontally polarized fields on each of the four sides.
- f. For the actual test configuration, please refer to the related Item –EUT Test Photos.

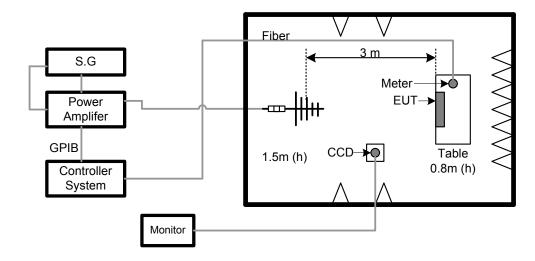
5.5.4 DEVIATION FROM TEST STANDARD

No deviation

Report No.: BTL-EMC-1-1503C222 Page 30 of 53



5.5.5 TEST SETUP



Note:

TABLE-TOP EQUIPMENT

The EUT installed in a representative system as described in section 7 of IEC/EN 61000-4-3 was placed on a non-conductive table 0.8 meters in height. The system under test was connected to the power and signal wire according to relevant installation instructions.

FLOOR-STANDING EQUIPMENT

The EUT installed in a representative system as described in section 7 of IEC/EN 61000-4-3 was placed on a non-conductive wood support 0.1 meters in height. The system under test was connected to the power and signal wire according to relevant installation instructions.

Report No.: BTL-EMC-1-1503C222 Page 31 of 53



5.5.6 TEST RESULTS

E.U.T:	Gaming Mouse Mat	Model Name :	RZ02-0135
Temperature :	25° C	Relative Humidity:	60 %
Pressure:	1002 hPa	Test Voltage :	AC 230V/50Hz
Test Mode :	USB		

Frequency Range RF Field		R.F.	Azimuth	Criteria	Results	Judgment
(MHz)	Position Field Strength		AZIIIIUIII			
	H/V	3 V/m (rms)	0			PASS
80 - 1000		AM	90			
80 - 1000		Modulated	180	Α	Α	
		1000Hz, 80%	270			

Note:

- 1) P/N denotes the Positive/Negative polarity of the output voltage.
- 2) N/A denotes test is not applicable to this device.
- 3) Criteria A: No observation of any performance degradation.
- 4) Criteria B: Some degradation of performance is observed but the equipment continues to operate as intended.
- 5) Criteria C: Loss of functionality, but self-recoverable by user, without loss of information or settings.

Report No.: BTL-EMC-1-1503C222 Page 32 of 53



5.6 EFT/BURST TESTING

5.6.1 TEST SPECIFICATION

Basic Standard:	IEC/EN 61000-4-4
Required Performance	В
Test Voltage:	Power Line: ±1 kV
	Signal/Control Line: ±0.5 kV
Polarity:	Positive & Negative
Impulse Frequency:	5 kHz
Impulse Wave shape :	5/50 ns
Burst Duration:	15 ms
Burst Period:	300 ms
Test Duration:	Not less than 1 min.

5.6.2 MEASUREMENT INSTRUMENTS

Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Calibrated until
1	THE MODULAR SOLUTION FOR 6 KV APPLICATIONS	Teseq	NSG 3060	1423	Aug. 29, 2015
2	Measurement Software	Teseq	Win 3000 Version 1.2.0	N/A	N /A

Remark: "N/A" denotes no model name, serial no. and no calibration specified.

5.6.3 TEST PROCEDURE

The EUT and support equipment(s) are placed on a table that is 0.8 meter high above a metal ground plane and should be located 0.1m+/-0.01m high above the Ground Reference Plane (1m*1m min. and 0.65mm thick min).

The other condition as following manner:

- a. The length of power cord between the coupling device and the EUT should not exceed 1
- b. Both positive and negative polarity discharges were applied.
- c. The duration time of each test sequential was 1 minute
- d. For the actual test configuration, please refer to the related Item –EUT Test Photos.

5.6.4 DEVIATION FROM TEST STANDARD

No deviation

Report No.: BTL-EMC-1-1503C222 Page 33 of 53



5.6.5 TEST SETUP ≥0,5 m ▶>0,5 m >0,5 m 1,0 m >0,5 m >0,5 m ΑE AC mains 0,5 m supply Capacitive coupling AC mains EUT supply clamp 0,1 m EFT/B AE generator (A) Insulating Contact to the ground support reference plane Coupling/ Insulating decoupling network (A) EFT/B Grounding connection according to the manufacturer's specification Length to be specified in the test plan support generator (B) Ground reference plane Grounding cable 1,0 m 1,0 m EUT EUT Capacitive coupling clamp AC mains supply AC mains supply 0,1 m 0,1 m 0,1 m Insulating / Insulating / Ground reference support support plane Grounding connection according to / the manufacturer's specification Length to be specified in the test plan Grounding connection according to the manufacturer's specification Length to be specified in the test plan To EFT/B generator



NI	~ +~
-17	()

TABLE-TOP EQUIPMENT

The configuration consisted of a wooden table (0.8m high) standing on the Ground Reference Plane. The GRP consisted of a sheet of aluminum (at least 0.25mm thick and 2.5m square) connected to the protective grounding system. A minimum distance of 0.5m was provided between the EUT and the walls of the laboratory or any other metallic structure.

FLOOR-STANDING EQUIPMENT

The EUT installed in a representative system as described in section 7 of IEC/EN 61000-4-4 and its cables, were isolated from the Ground Reference Plane by an insulating support that is 0.1-meter thick. The GRP consisted of a sheet of aluminum (at least 0.25mm thick and 2.5m square) connected to the protective grounding system.

Report No.: BTL-EMC-1-1503C222 Page 35 of 53



5.6.6 TEST RESULTS

E.U.T:	Gaming Mouse Mat	Model Name :	RZ02-0135
Temperature :	25° C	Relative Humidity:	60 %
Pressure :	1002 hPa	Test Voltage :	AC 230V/50Hz
Test Mode:	USB		

Mode	(V) AC Power Line		() DC Power Line		() Signal/Control Line	
Test Level 1kV		κV	0.5kV		0.5kV	
Port(s)	Polarity	Results	Polarity	Results	Polarity	Results
Line (L)	Р	А	Р	-	Р	-
Line (L)	N	А	N	-	N	-
Neutral (N)	Р	А	Р	-	Р	-
Neutral (N)	N	А	N	-	N	-
Ground (PE)	Р	А	Р	-	Р	-
Giodila (FL)	N	Α	N	-	N	-
Signal/Control	Р	-	Р	-	Р	-
Line	N	-	N	-	N	-
Criteria	B A		В		В	
Result			N/A		N/A	
Judgment	PA	SS	N/A		N/A	

Note:

- 1) P/N denotes the Positive/Negative polarity of the output voltage.
- 2) N/A denotes test is not applicable to this device
- 3) Criterion A: No observation of any performance degradation.
- 4) Criterion B: Some degradation of performance is observed but the equipment continues to operate as intended.
- 5) Criterion C: Loss of functionality, but self-recoverable by user, without loss of information or settings.

Report No.: BTL-EMC-1-1503C222 Page 36 of 53



5.7 SURGE TESTING

5.7.1 TEST SPECIFICATION

Basic Standard:	IEC/EN 61000-4-5
Required Performance	В
Wave-Shape:	Combination Wave
	1.2/50 us Open Circuit Voltage
	8 /20 us Short Circuit Current
Test Voltage :	Power Line: ±0.5 kV, ±1 kV, ±2 kV
Surge Input/Output:	L1-L2, L1-PE, L2-PE
Generator Source:	2 ohm between networks
Impedance:	12 ohm between network and ground
Polarity:	Positive/Negative
Phase Angle:	0 /90/180/270
Pulse Repetition Rate:	1 time / min. (maximum)
Number of Tests:	5 positive and 5 negative at selected points

5.7.2 MEASUREMENT INSTRUMENTS

Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Calibrated until
	THE MODULAR				
1	SOLUTION FOR 6 KV APPLICATIONS	Teseq	NSG 3060	1423	Aug. 29, 2015
2	Measurement Software	Teseq	Win 3000 Version 1.2.0	N/A	N /A

Remark: "N/A" denotes no model name, serial no. and no calibration specified.

5.7.3 TEST PROCEDURE

a. For EUT power supply:

The surge is to be applied to the EUT power supply terminals via the capacitive coupling network. Decoupling networks are required in order to avoid possible adverse effects on equipment not under test that may be powered by the same lines, and to provide sufficient decoupling impedance to the surge wave. The power cord between the EUT and the coupling/decoupling networks shall be 2meters in length (or shorter).

- b. For test applied to unshielded unsymmetrically operated interconnection lines of EUT:

 The surge is applied to the lines via the capacitive coupling. The coupling /decoupling networks shall not influence the specified functional conditions of the EUT. The interconnection line between the EUT and the coupling/decoupling networks shall be 2 meters in length (or shorter).
- c. For test applied to unshielded symmetrically operated interconnection /telecommunication lines of EUT:
 - The surge is applied to the lines via gas arrestors coupling. Test levels below the ignition point of the coupling arrestor cannot be specified. The interconnection line between the EUT and the coupling/decoupling networks shall be 2 meters in length (or shorter).
- d. For the actual test configuration, please refer to the related Item –EUT Test Photos.

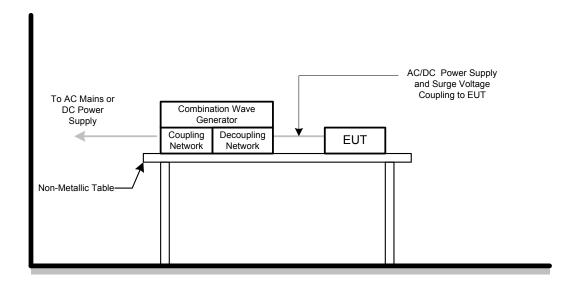
Report No.: BTL-EMC-1-1503C222 Page 37 of 53



5.7.4 DEVIATION FROM TEST STANDARD

No deviation

5.7.5 TEST SETUP



Report No.: BTL-EMC-1-1503C222 Page 38 of 53



5.7.6 TEST RESULTS

E.U.T:	Gaming Mouse Mat	Model Name :	RZ02-0135
Temperature :	25° C	Relative Humidity:	60 %
Pressure:	1002 hPa	Test Voltage :	AC 230V/50Hz
Test Mode :	USB		

Wave Form	1.2/50(8/20)Ti/Th us								
EUT Ports	Polarity	Phase			age		Criteria	Result	Judgment
Tested	1 Oldrity	1 11450	0.5 kV	1kV	1.5kV	2kV			
	+/-	0°	Α	Α	-	ı			
L - N	+/-	90°	Α	Α	-	ı	В	^	PASS
L - IN	+/-	180°	Α	Α	-	-	Б	A	PASS
	+/-	270°	Α	Α	-	-			
	+/-	0°	Α	Α	Α	Α		ВА	PASS
L - PE	+/-	90°	Α	Α	Α	Α	В		
L-PC	+/-	180°	Α	Α	Α	Α	ь		
	+/-	270°	Α	Α	Α	Α			
	+/-	0°	Α	Α	Α	Α			PASS
N - PE	+/-	90°	Α	Α	Α	Α	В	Α	
N-FE	+/-	180°	Α	Α	Α	Α	В	S A	PASS
	+/-	270°	Α	Α	Α	Α		_	
Signal Line (N/A)	+/-	N/A	-	-	-	1	В	N/A	N/A

Note:

- 1) Polarity and Numbers of Impulses: 5 Pst / Ngt at each tested mode
- 2) N/A denotes test is not applicable to this device
- 3) Criteria A: No observation of any performance degradation.
- 4) Criteria B: Some degradation of performance is observed but the equipment continues to operate as intended.
- 5) Criteria C: Loss of functionality, but self-recoverable by user, without loss of information or settings.

Report No.: BTL-EMC-1-1503C222 Page 39 of 53



5.8 INJECTION CURRENT TESTING

5.8.1 TEST SPECIFICATION

Basic Standard:	IEC/EN 61000-4-6
Required Performance	A
Frequency Range:	0.15 MHz - 80 MHz
Field Strength:	3 Vr.m.s.
Modulation:	1kHz Sine Wave, 80%, AM Modulation
Frequency Step:	1% of fundamental
Dwell Time:	at least 3 seconds

5.8.2 MEASUREMENT INSTRUMENTS

Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Calibrated until
1	Signal Generator	HP	8648A	3636A02964	Mar. 28, 2016
2	Power Amplifier	Teseq	CBA230M-080	T43748	Mar. 28, 2016
3	Power CDN	FCC	FCC-801-M2/M3-16A	100270	Mar. 28, 2016
4	Power CDN	FCC	FCC-801-M2/M3-16A	100271	Mar. 28, 2016
5	Measurement Software	TOYO	IM5/C Ver 3.7.028	N/A	N/A

Remark: "N/A" denotes no model name, serial no. and no calibration specified.

5.8.3 TEST PROCEDURE

The EUT and support equipment, are placed on a table that is 0.8 meter above a metal ground plane measured 1m*1m min. and 0.65mm thick min.

The other condition as following manner:

- a. The field strength level was 3V.
- b. The frequency range is swept from 150 KHz to 80 MHz, with the signal 80% amplitude modulated with a 1kHz sine wave. The rate of sweep did not exceed 1.5x 10-3 decade/s. Where the frequency range is swept incrementally, the step size was 1% of fundamental.
- c. The dwell time at each frequency shall be not less than the time necessary for the EUT to be able to respond.
- d. For the actual test configuration, please refer to the related Item –EUT Test Photos.

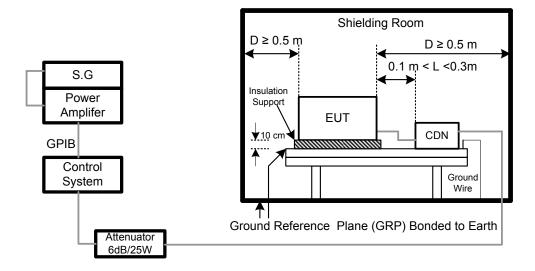
5.8.4 DEVIATION FROM TEST STANDARD

No deviation

Report No.: BTL-EMC-1-1503C222 Page 40 of 53



5.8.5 TEST SETUP



For the actual test configuration, please refer to the related Item –EUT Test Photos.

NOTE:

FLOOR-STANDING EQUIPMENT

The equipment to be tested is placed on an insulating support of 0.1 meters height above a ground reference plane. All relevant cables shall be provided with the appropriate coupling and decoupling devices at a distance between 0.1 meters and 0.3 meters from the projected geometry of the EUT on the ground reference plane.

Report No.: BTL-EMC-1-1503C222 Page 41 of 53



5.8.6 TEST RESULTS

E.U.T:	Gaming Mouse Mat	Model Name :	RZ02-0135
Temperature :	25° C	Relative Humidity:	60 %
Pressure :	1002 hPa	Test Voltage :	AC 230V/50Hz
Test Mode :	USB		

Test Ports (Mode)	Freq. Range (MHz)	Field Strength	Criteria	Results	Judgment
Input/ Output AC. Power Port	0.1580		A	Α	PASS
Input/ Output DC. Power Port	0.15 80	3V(rms) AM Modulated 1000Hz, 80%	Α	N/A	N/A
Signal Line (N/A)	0.15 80		A	N/A	N/A

Note:

- 1) N/A denotes test is not applicable to this device.
- 2) Criteria A: No observation of any performance degradation.
- 3) Criteria B: Some degradation of performance is observed but the equipment continues to operate as intended.
- 4) Criteria C: Loss of functionality, but self-recoverable by user, without loss of information or settings.

Report No.: BTL-EMC-1-1503C222 Page 42 of 53



5.9 POWER FREQUENCY MAGNETIC FIELD TESTING

5.9.1 TEST SPECIFICATION

Basic Standard:	IEC/EN 61000-4-8
Required Performance	A
Frequency Range:	50Hz/60Hz
Field Strength:	1 A/m
Observation Time:	1 minute
Inductance Coil:	Rectangular type, 1mx1m

5.9.2 MEASUREMENT INSTRUMENTS

Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Calibrated until
1	Magnetic Field Test Generator	FCC	F-1000-4-8- G-125A	04032	Mar. 28, 2016
2	Magnetic Field immunity loop	Thermo KeyTek	F-1000-4-8/9 /10-L-1M	04024	Mar. 28, 2016

Remark: "N/A" denotes no model name, serial no. and no calibration specified.

5.9.3 TEST PROCEDURE

The EUT and support equipment, are placed on a table that is 0.8 meter above a metal ground plane measured 1m*1m min. and 0.65mm thick min.

The other condition as following manner:

- a. The equipment cabinets shall be connected to the safety earth directly on the GRP via the earth terminal of the EUT.
- b. The cables supplied or recommended by the equipment manufacturer shall be used. 1 meter of all cables used shall be exposed to the magnetic field.
- c. For the actual test configuration, please refer to the related Item –EUT Test Photos.

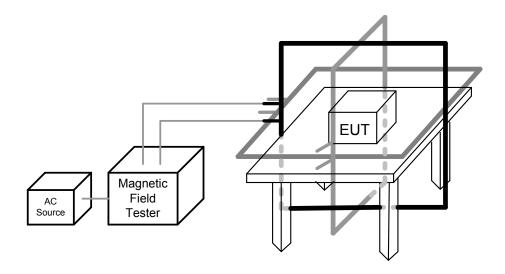
5.9.4 DEVIATION FROM TEST STANDARD

No deviation

Report No.: BTL-EMC-1-1503C222 Page 43 of 53



5.9.5 TEST SETUP



Note:

TABLE-TOP EQUIPMENT

The equipment shall be subjected to the test magnetic field by using the induction coil of standard dimension (1 m x 1 m). The induction coil shall then be rotated by 90 degrees in order to expose the EUT to the test field with different orientations.

FLOOR-STANDING EQUIPMENT

The equipment shall be subjected to the test magnetic field by using induction coils of suitable dimensions. The test shall be repeated by moving and shifting the induction coils, in order to test the whole volume of the EUT for each orthogonal direction. The test shall be repeated with the coil shifted to different positions along the side of the EUT, in steps corresponding to 50% of the shortest side of the coil. The induction coil shall then be rotated by 90 degrees in order to expose the EUT to the test field with different orientations.

Report No.: BTL-EMC-1-1503C222 Page 44 of 53



5.9.6 TEST RESULTS

E.U.T:	Gaming Mouse Mat	Model Name :	RZ02-0135
Temperature :	25° C	Relative Humidity:	60 %
Pressure:	1026 hPa	Test Voltage :	AC 230V/50Hz
Test Mode :	USB		

50Hz

Test Mode	Test Level	Antenna aspect	Duration (s)	Criteria	Results	Judgment
Enclosure	1 A/m	X	60 s	Α	Α	PASS
Enclosure	1 A/m	Y	60 s	Α	Α	PASS
Enclosure	1 A/m	Z	60 s	Α	Α	PASS

60Hz

00112						
Test Mode	Test Level	Antenna aspect	Duration (s)	Criteria	Results	Judgment
Enclosure	1 A/m	X	60 s	Α	Α	PASS
Enclosure	1 A/m	Y	60 s	Α	Α	PASS
Enclosure	1 A/m	Z	60 s	Α	Α	PASS

Note:

- 1) N/A denotes test is not applicable to this device
- 2) Criteria A: No observation of any performance degradation.
- 3) Criteria B: Some degradation of performance is observed but the equipment continues to operate as intended.
- 4) Criteria C: Loss of functionality, but self-recoverable by user, without loss of information or settings.

Report No.: BTL-EMC-1-1503C222 Page 45 of 53



5.10 VOLTAGE INTERRUPTION/DIPS TESTING

5.10.1 TEST SPECIFICATION

Basic Standard:	IEC/EN 61000-4-11	
Required Performance	B (For >95% Voltage Dips)	
	C (For 30% Voltage Dips)	
	C (For >95% Voltage Interruptions)	
Test Duration Time:	Minimum three test events in sequence	
Interval between Event:	Minimum ten seconds	
Phase Angle:	0°/45°/90°/135°/180°/225°/270°/315°/360°	
Test Cycle:	3 times	

5.10.2 MEASUREMENT INSTRUMENTS

Item	Kind of Equipment	Manufacturer	Type No.	Serial No.	Calibrated until
1	THE MODULAR SOLUTION FOR 6 KV APPLICATIONS	Teseq	NSG 3060	1423	Aug. 29, 2015
2	Measurement Software	Teseq	Win 3000 Version 1.2.0	N/A	N /A

Remark: "N/A" denotes no model name, serial no. and no calibration specified.

5.10.3 TEST PROCEDURE

The EUT shall be tested for each selected combination of test levels and duration with a sequence of three dips/interruptions with intervals of 10 s minimum (between each test event). Each representative mode of operation shall be tested. Abrupt changes in supply voltage shall occur at zero crossings of the voltage waveform.

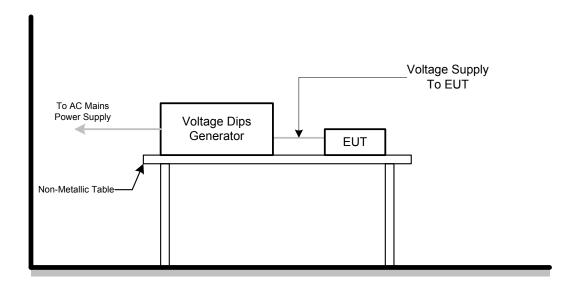
5.10.4 DEVIATION FROM TEST STANDARD

No deviation

Report No.: BTL-EMC-1-1503C222 Page 46 of 53



5.10.5 TEST SETUP



For the actual test configuration, please refer to the related Item –EUT Test Photos.

Report No.: BTL-EMC-1-1503C222 Page 47 of 53



5.10.6 TEST RESULTS

E.U.T:	Gaming Mouse Mat	Model Name :	RZ02-0135
Temperature :	25° C	Relative Humidity:	60 %
Pressure :	1002 hPa	Test Voltage :	AC 230V/50Hz
Test Mode :	USB		

AC 230V/50Hz					
Voltage Reduction	Periods	Criteria	Results	Judgment	
Voltage dip >95%	0.5	В	A	PASS	
Voltage dip 30%	25	С	A	PASS	
Interruption>95%	250	С	С	PASS	

AC 100V/50Hz					
Voltage Reduction	Periods	Criteria	Results	Judgment	
Voltage dip >95%	0.5	В	A	PASS	
Voltage dip 30%	25	С	С	PASS	
Interruption>95%	250	С	С	PASS	

AC 240V/50Hz					
Voltage Reduction	Periods	Criteria	Results	Judgment	
Voltage dip >95%	0.5	В	Α	PASS	
Voltage dip 30%	25	С	A	PASS	
Interruption>95%	250	С	С	PASS	

Note:

- 1) N/A denotes test is not applicable to this device.
- 2) Criteria A: No observation of any performance degradation.
- 3) Criteria B: Some degradation of performance is observed but the equipment continues to operate as intended.
- 4) Criteria C: Loss of functionality, but self-recoverable by user, without loss of information or settings.

Report No.: BTL-EMC-1-1503C222 Page 48 of 53



6. EUT TEST PHOTO

Conducted Measurement Photos

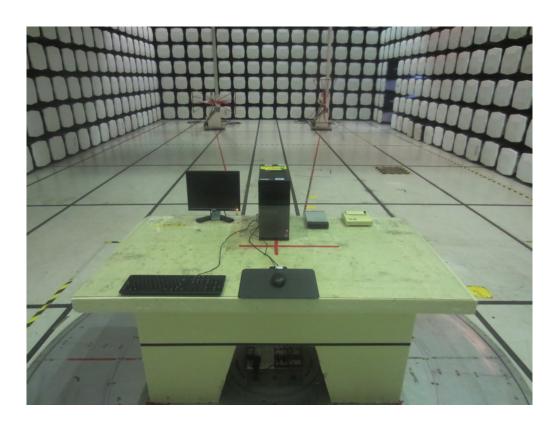


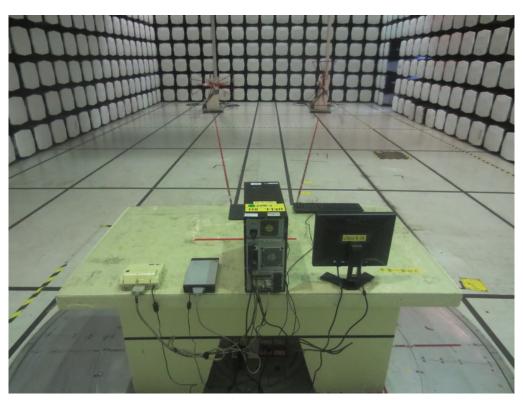


Report No.: BTL-EMC-1-1503C222 Page 49 of 53



Radiated Measurement Photos(BETWEEN 30MHZ AND 1000MHZ)





Report No.: BTL-EMC-1-1503C222 Page 50 of 53











Report No.: BTL-EMC-1-1503C222 Page 51 of 53







cs



Report No.: BTL-EMC-1-1503C222 Page 52 of 53







Report No.: BTL-EMC-1-1503C222 Page 53 of 53